

# X-Ray and Electron Probing Applications

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### **Capacitor Failure Investigation**

### **Equipment Used**

• Dye and Pry Technique



Capacitor: 3D X-Ray Image



3D X-Ray: Open Terminal observed



X-section Optical Image

- Separation of terminal from the electrode as the failure site confirmed
- 3D X-Ray helped identify the cross-section site for further failure investigation



# PCBA Open Trace Failure Investigation

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM



Capacitor: 3D X-Ray Image, cross section view



3D X-Ray: Open Terminal observed

- Cracks observed in both vias from X-Ray imaging confirmed by SEM
- 3D X-Ray helped identify the cross-section site for further failure investigation



### PCBA BGA Solder Joint Delamination

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

#### 3D X-Ray Images







#### SEM Images







#### **Conclusions**

• Solder joints delamination on the chip side observed in 3D X-Ray and confirmed by SEM Imaging



### PCBA BGA Solder Joint Delamination

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

#### 3D X-Ray Image



#### SEM Image



#### <u>Crack observed in 3D X-Ray imaging and</u> <u>confirmed by SEM imaging</u>





# Manufacturing Defect in a Cable Connector Assembly

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM



- Insufficient soldering observed in the 3D X-Ray imaging and confirmed by SEM imaging
- Combination of techniques: useful tool for quality / inspection applications



### Low Power Transceiver Failure Analysis

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

### Failure Mode

• 3-pt Mechanical Bend Test



- Overstress failure resulting in delamination at multiple interfaces (PCBA-Bond Pad and Solder-Bond Pad
- Obvious failures-eliminating the need for one of the tools either SEM or X-Ray depending on destructive or non-destructive technique



# Network Interface Card Failure Analysis

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

### Failure Mode

Mechanical Overstress Test



- Overstress failure resulting in delamination at multiple interfaces (PCBA-Bond Pad and Solder-Bond Pad
- Obvious failures-eliminating the need for one of the tools either SEM or X-Ray depending on destructive or non-destructive technique



# Quality Inspection of a Cell Phone Cable Connector

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM



3D X-Ray Image

SEM Image after x-section

### **Conclusions**

• Bridging of joints – highlighting the importance of 3D X-Ray as a quick and effective inspection tool



# Cell Phone PCBA CPU Failure Analysis

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

### Failure Mode

Mechanical Bend Test



- Overstress failure resulting in delamination at multiple interfaces (PCBA-Bond Pad and Solder-Bond Pad
- Failure confirmation from X-Ray eliminates the need for SEM if non-destructive technique is called for



## Cell Phone PCBA CPU Failure Analysis

### **Equipment Used**

• 3D X-Ray followed by X-section / SEM

### Failure Mode

Mechanical Bend Test





3D X-Ray Image